

AI  
cont

larger than an average value of video signal levels of the surrounding pixels and a difference value (difference) obtained by subtracting the average value from the value of the defect signal level is also large. Further, the present invention is based on the inventors' further discovery that when a defective pixel is present, only one of a plurality of pixels in the corresponding same image-pickup position among a plurality of solid-state image-pickup devices corresponding to spectral lights for R, G and B in the image-pickup apparatus may be defective, that is, two or more pixels of them may be not defective simultaneously.

---

Page 11, please amend the paragraph beginning at line 18 as follows:

A2

Description is now made to a general situation in which the inventive defective pixel detecting method may be suitably applied in the case where a white defect occurs in a video image due to a defective pixel.

---

Page 11, please amend the paragraph beginning at line 23 as follows:

A13

A defect signal level of a defective pixel causing a white defect appears as a peak component having a signal level higher than video signal levels of surrounding pixels thereof. Accordingly, a value of the video signal (defect signal) level of the defective pixel causing the white noise is relatively larger than an average value of the video signal levels of the surrounding pixels and a difference value (difference) obtained by subtracting the average value from the value of the defect signal level is also large similarly.

---

Page 13, please amend the paragraph beginning at line 1 as follows:

A4

Further, for example, when it is assumed that a certain inspected pixel of an R channel is a white defect causing defective pixel, the possibility that any one or

At cont  
both of pixels of G and B channels at the image-pickup point of the incident (imaging) light corresponding to the inspected pixel of R channel are also defective similarly to the inspected pixel of the R channel is very small. That is, it can be safely said that only one pixel of the R, G and B channel pixels corresponding to any image-pickup point in the incident light is defective at the most.

---

Page 13, please amend the paragraph beginning at line 12 as follows:

---

AB  
Accordingly, in an example where an inspected pixel for R channel corresponding to a certain image-pickup point within incident light to be imaged is assumed to have a white defect, it is considered that a difference value between a signal level of the inspected pixel of R channel and an average value of signal levels of surrounding pixels thereof is relatively large as described above, and a difference value between a signal level of a pixel of G channel corresponding to the image-pickup point and an average value of signal levels of surrounding pixels thereof and a difference value between a signal level of a pixel of B channel and an average value of signal levels of surrounding pixels thereof are relatively small even in either case of G and B channels.

---

Page 23, please amend the paragraph beginning at line 19 as follows:

---

AB  
Further, control as to whether correction is made for each defective pixel in accordance with a defect signal level of a detected defective pixel or not can be made externally and the defect signal level of the defective pixel or the correction coefficient for the defective pixel correction can be changed in accordance with image conditions (presence of storage, storage time, degree of video gain and the like). For example, a white defect detection level (W) can be changed in accordance with a storage time so that increased and reduced white defect caused by change